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# Information Security and Internet of Things (IoT) Security: Embedded Digital Forensics

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Deadline for manuscript submissions:

closed (15 October 2023)

## **Message from the Guest Editors**

Dear Colleagues,

This Special Issue is intended to study the advances in security and digital forensic analysis issues concerning embedded devices (from IoT nodes, through mobile processors, connected vehicles, and industrial systems, to home routers, etc.). These are systems that are part of the everyday life of citizens and are therefore a risk in the development of daily activities. This amount of technology represents a widespread attack surface that can be exploited by malicious actors, including the following topics:

- connected cars
- reverse engineering
- IOI
- cryptography
- TPM
- smartphones
- hash cracking
- credential spoofing
- vulnerabilities
- attacks

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# **Message from the Editor-in-Chief**

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